

Monday, August 25th 2014

8:45-9:00	Opening of the Course on "Reliability and Variability of Electronic Devices"
9:00-11:00	Felice Crupi, Università della Calabria (IT), "Reliability models: from basic theory to application to CMOS nanodevices"
11:00-11:30	Break
11:30-13:00	Ben Kaczer, imec (BE), "Advanced CMOS Devices and Reliability"
13:00-14:00	Lunch
14:00-15:30	Ben Kaczer, imec (BE), "Atomistic Perspective of Device Reliability"
15:30-16:00	Break
16:00-18:00	Jacopo Franco, imec (BE), "Reliability and time-dependent variability of high-mobility devices: SiGe, Ge, and InGaAs technologies"
20:00	Dinner

Tuesday, August 26th 2014

9:00-11:00	Gerard Ghibaudo, IMEP-LAHC (FR), "Impact of low frequency noise on the reliability and variability of nano CMOS devices"
11:00-11:30	Break
11:30-13:00	Tibor Grasser, University of Technology of Vienna (AT), "Bias Temperature Instability in CMOS nanodevices"
13:00-14:00	Lunch
14:00-15:30	Tibor Grasser, University of Technology of Vienna (AT), "Bias Temperature Instability in CMOS nanodevices"
15:30-16:00	Break
16:00-18:00	Enrique Miranda, Autonomous University of Barcelona (ES), "Physics and Spatial Statistics of Multifilamentary Conduction Patterns in MIS/MIM Devices"
20:00	Dinner

Wednesday, August 27th 2014

9:00-10:30	Salvatore Amoroso, University of Glasgow (UK) "Variability of CMOS nanodevices"
10:30-11:00	Break
11:00-12:30	Salvatore Amoroso, University of Glasgow (UK) "Variability of CMOS nanodevices"
12:30-14:00	Lunch
14:00-15:30	Andreas Kerber, Globalfoundries (US), "Reliability of CMOS nanodevices"
15:30-16:00	Break
16:00-17:30	Andreas Kerber, Globalfoundries (US), "Reliability of CMOS nanodevices"
20:00	Social dinner

Thursday, August 28th 2014

9:00-11:00	Susanna Reggiani, Università di Bologna (IT), "Modeling and characterization of hot-carrier stress degradation in Power MOSFETs"
11:00-11:30	Break
11:30-13:00	Paolo Magnone, Università di Bologna (IT), "Reliability issues in vertical power MOSFETs"
13:00-14:00	Lunch
14:00-16:00	Antonio Andreini, ST-Microelectronics (IT), "Reliability challenges in Smart Power technologies and products"
20:00	Dinner

Friday, August 29th 2014

9:00-10:30	Gaudenzio Meneghesso, Università di Padova (IT), "Reliability of GaN power devices"
10:30-11:00	Break
11:00-12:30	Gaudenzio Meneghesso, Università di Padova (IT), "Reliability of GaN power devices"
12:30-14:15	Lunch